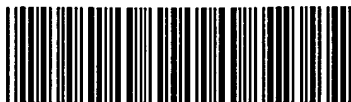


Search Notes



Application/Control No.

10/649,671

Examiner

Hong C. Kim

Applicant(s)/Patent under
Reexamination

HIRAIWA ET AL.

Art Unit

2186

SEARCHED

Class	Subclass	Date	Examiner
711	112 170 173	8/15/05	rdh
	203		
	4 6		
713	100		
709	226		
714	007		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	8/15/05	rdh